onsemi

Field Stop Trench IGBT 650 V, 75 A

FGHL75T65MQDT

Field stop 4th generation mid speed IGBT technology copacked with full rated current diode.

Features

- Maximum Junction Temperature: $T_J = 175^{\circ}C$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage: $V_{CE(Sat)} = 1.45 V (Typ.) @ I_C = 75 A$
- 100% of the Parts are Tested for I_{LM} (Note 2)
- Smooth and Optimized Switching
- Tight Parameter Distribution
- RoHS Compliant

Typical Applications

- Solar Inverter
- UPS, ESS
- PFC, Converters

MAXIMUM RATINGS

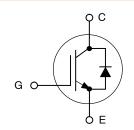
Rating	Symbol	Value	Unit
Collector-to-Emitter Voltage	V_{CES}	650	V
Gate-to-Emitter Voltage Transient Gate-to-Emitter Voltage	V _{GES}	±20 ±30	V
$ \begin{array}{llllllllllllllllllllllllllllllllllll$	Ι _C	80 75	A
Pulsed Collector Current (Note 2)	I _{LM}	300	А
Pulsed Collector Current (Note 3)	I _{CM}	300	А
Diode Forward Current (Note 1) @ $T_{C =} 25^{\circ}C$ @ $T_{C =} 100^{\circ}C$	١ _F	80 75	A
Pulsed Diode Maximum Forward Current	I _{FM}	300	А
$ \begin{array}{ll} \mbox{Maximum Power Dissipation} & @\ T_C = 25^\circ C \\ & @\ T_C = 100^\circ C \end{array} $	P _D	375 188	W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	–55 to +175	°C
Maximum Lead Temp. for Soldering Purposes (1/8" from case for 5 s)	ΤL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Value limit by bond wire

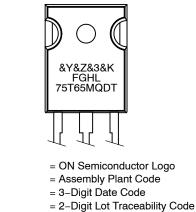
- 2. V_{CC} = 400 V, V_{GE} = 15 V, I_C = 300 A, R_G = 9 Ω , Inductive Load, 100% tested
- 3. Repetitive rating: pulse width limited by max. junction temperature

75 A, 650 V V_{CESat} = 1.45 V





MARKING DIAGRAM



&K = 2-Digit Lot Traceability Code FGHL75T65MQDT = Specific Device Code

&Y

&Ζ

&3

ORDERING INFORMATION

Device	Package	Shipping
FGHL75T65MQDT	TO-247-3L	30 Units / Tube

THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case, for IGBT	$R_{ extsf{ heta}JC}$	0.40	°C/W
Thermal resistance junction-to-case, for Diode	$R_{ extsf{ heta}JC}$	0.60	°C/W
Thermal resistance junction-to-ambient	$R_{ hetaJA}$	40	°C/W

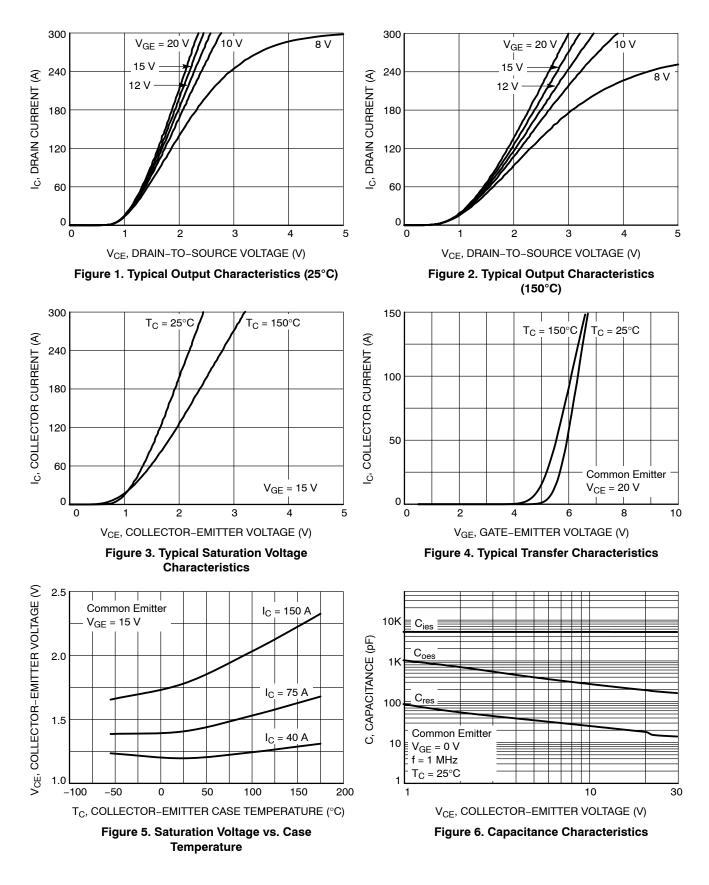
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)

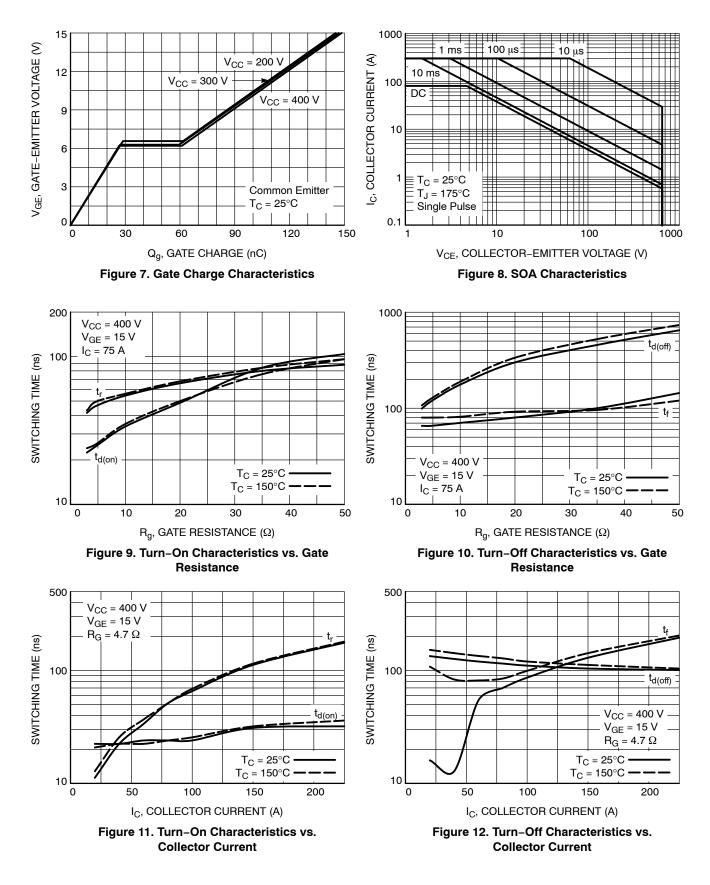
Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•					•
Collector-emitter breakdown voltage, gate-emitter short-circuited	V _{GE} = 0 V, I _C = 1 mA	BV _{CES}	650	-	-	V
Temperature Coefficient of Breakdown Voltage	V _{GE} = 0 V, I _C = 1 mA	$\frac{\Delta BV_{CES}}{\Delta T_{J}}$	-	0.6	-	V/°C
Collector-emitter cut-off current, gate-emitter short-circuited	V _{GE} = 0 V, V _{CE} = 650 V	I _{CES}	-	-	250	μΑ
Gate leakage current, collector-emitter short-circuited	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	-	-	±400	nA
ON CHARACTERISTICS						-
Gate-emitter threshold voltage	$V_{GE} = V_{CE}$, $I_C = 75 \text{ mA}$	V _{GE(th)}	3.0	4.5	6.0	V
Collector-emitter saturation voltage	V_{GE} = 15 V, I _C = 75 A, T _J = 25°C V _{GE} = 15 V, I _C = 75 A, T _J = 150°C	V _{CE(sat)}	-	1.45 1.65	1.8 -	V
DYNAMIC CHARACTERISTICS						
Input capacitance	V _{CE} = 30 V,	C _{ies}	-	4954	-	pF
Output capacitance	V _{GE} = 0 V, f = 1 MHz	C _{oes}	_	163	-	
Reverse transfer capacitance		C _{res}	_	14	-	
Gate charge total	V _{CE} = 400 V,	Qg	_	149	-	nC
Gate-to-emitter charge	I _C = 75 A, V _{GE} = 15 V	Q _{ge}	-	27	-	
Gate-to-collector charge		Q _{gc}	-	34	-	
SWITCHING CHARACTERISTICS, INDUC	TIVE LOAD					-
Turn-on delay time	$T_{\rm C} = 25^{\circ}{\rm C},$	t _{d(on)}	-	22	-	ns
Rise time	V _{CC} = 400 V, I _C = 37.5 A,	t _r	-	21	-	
Turn-off delay time	R _G = 4.7 Ω, V _{GE} = 15 V,	t _{d(off)}	-	125	-	
Fall time	Inductive Load	t _f	-	11	-	
Turn-on switching loss		Eon	-	0.86	-	mJ
Turn-off switching loss		E _{off}	-	0.49	-	7
Total switching loss		E _{ts}	_	1.35	-	
Turn-on delay time	$T_{C} = 25^{\circ}C,$ $V_{CC} = 400 \text{ V},$ $I_{C} = 75 \text{ A},$ $R_{G} = 4.7 \Omega,$ $V_{GE} = 15 \text{ V},$ Inductive Load	t _{d(on)}	-	24	-	ns
Rise time		t _r	-	46	-	
Turn-off delay time		t _{d(off)}	-	118	-	
Fall time		t _f	-	66	-	
Turn-on switching loss		E _{on}	-	2.35	-	mJ
Turn-off switching loss		E _{off}	-	1.25	-	
Total switching loss	1	E _{ts}	_	3.6	-	

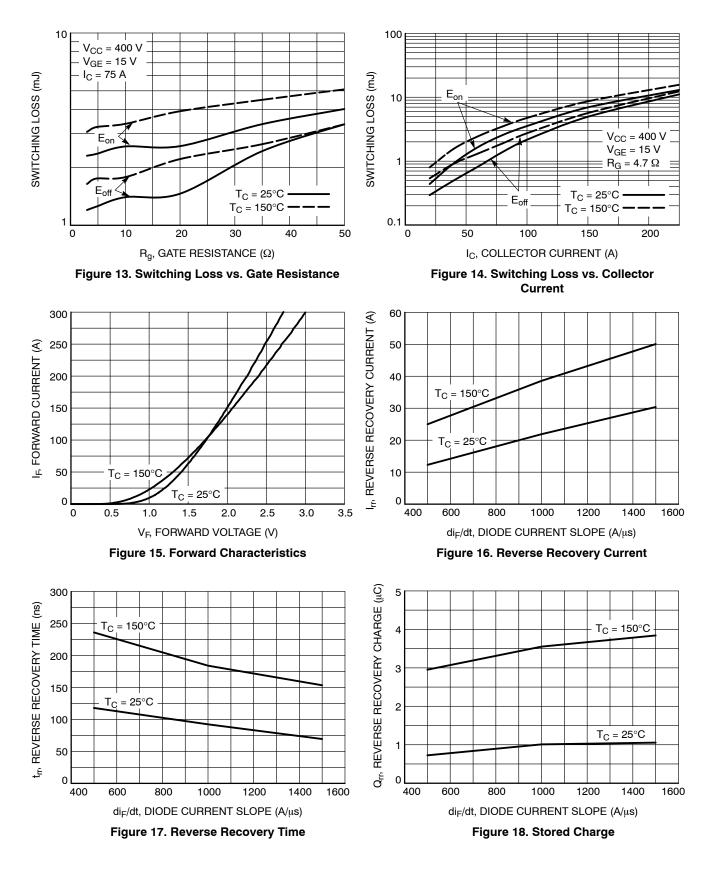
ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS, IND	UCTIVE LOAD					-
Turn-on delay time	$T_{\rm C} = 150^{\circ}{\rm C},$	t _{d(on)}	-	22	-	ns
Rise time	V _{CC} = 400 V, I _C = 37.5 A,	t _r	-	22	-	1
Turn-off delay time	R _G = 4.7 Ω, V _{GF} = 15 V,	t _{d(off)}	-	142	-	
Fall time	Inductive Load	t _f	-	85	-	
Turn-on switching loss		E _{on}	-	1.43	-	mJ
Turn-off switching loss		E _{off}	-	0.85	-	1
Total switching loss		E _{ts}	-	2.28	-	
Turn-on delay time	$T_{\rm C} = 150^{\circ}{\rm C},$	t _{d(on)}	-	24	-	ns
Rise time	$V_{CC} = 400 V,$ $I_{C} = 75 A,$	t _r	-	50	-	
Turn-off delay time	R _G = 4.7 Ω, V _{GF} = 15 V,	t _{d(off)}	-	126	-	
Fall time	Inductive Load	t _f	-	80	-	
Turn-on switching loss		Eon	-	3.24	-	mJ
Turn-off switching loss		E _{off}	-	1.75	-	1
Total switching loss		E _{ts}	-	4.99	-	
DIODE CHARACTERISTICS	·					
Diode Forward Voltage	$I_{F} = 75 \text{ A}, \text{ T}_{J} = 25^{\circ}\text{C}$	V _{FM}	-	1.65	2.1	V
	I _F = 75 A, T _J = 150°C		-	1.55	-	1
DIODE SWITCHING CHARACTERISTI	CS, INDUCTIVE LOAD					-
Reverse Recovery Energy	$T_{C} = 25^{\circ}C, V_{CE} = 400 \text{ V}, I_{F} = 37.5 \text{ A},$	E _{rec}	-	105	-	μJ
Diode Reverse Recovery Time	dl _F /dt = 1000 A/μs	T _{rr}	-	58	-	ns
Diode Reverse Recovery Charge		Q _{rr}	-	591	-	nC
Reverse Recovery Energy	$T_{C} = 25^{\circ}C, V_{CE} = 400 V, I_{F} = 75 A,$	E _{rec}	-	235	-	μJ
Diode Reverse Recovery Time	dl _F /dt = 1000 A/μs	T _{rr}	-	107	-	ns
Diode Reverse Recovery Charge		Q _{rr}	-	1113	-	nC
Reverse Recovery Energy	T_{C} = 150°C, V_{CE} = 400 V, I_{F} = 37.5 A,	E _{rec}	-	747	-	μJ
Diode Reverse Recovery Time	dl _F /dt = 1000 A/μs	T _{rr}	-	151	-	ns
Diode Reverse Recovery Charge		Q _{rr}	-	2780	-	nC
Reverse Recovery Energy	$T_{C} = 150^{\circ}C, V_{CE} = 400 V, I_{F} = 75 A,$	E _{rec}	-	865	-	μJ
Diode Reverse Recovery Time	dl _F /dt = 1000 A/μs	T _{rr}	-	171	-	ns
Diode Reverse Recovery Charge	1 1	Q _{rr}	_	3286	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.







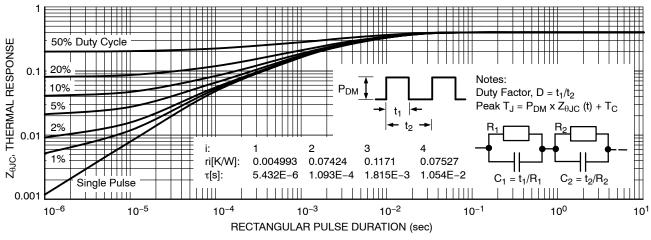


Figure 19. Transient Thermal Impedance of IGBT

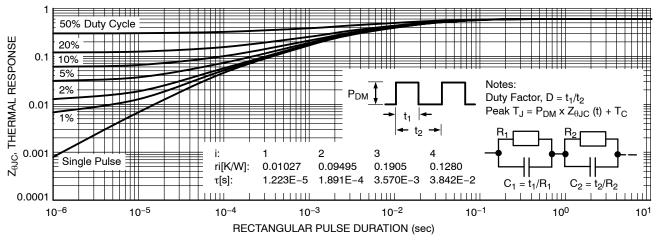
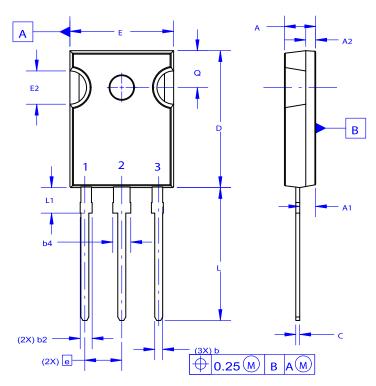


Figure 20. Transient Thermal Impedance of Diode

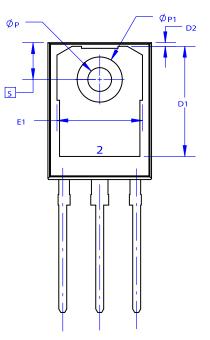
PACKAGE DIMENSIONS





NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
 D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1. E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.



DIM	MILLIMETERS			
DIN	MIN	NOM	MAX	
Α	4.58	4.70	4.82	
A1	2.20	2.40	2.60	
A2	1.40	1.50	1.60	
D	20.32	20.57	20.82	
E	15.37	15.62	15.87	
E2	4.96	5.08	5.20	
е	~	5.56	~	
L	19.75	20.00	20.25	
L1	3.69	3.81	3.93	
ØР	3.51	3.58	3.65	
Q	5.34	5.46	5.58	
S	5.34	5.46	5.58	
b	1.17	1.26	1.35	
b2	1.53	1.65	1.77	
b4	2.42	2.54	2.66	
с	0.51	0.61	0.71	
D1	13.08	~	~	
D2	0.51	0.93	1.35	
E1	12.81	~	~	
Ø P 1	6.60	6.80	7.00	

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